

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| Applicant: | Alistair C.H. Rowe, et al. | Examiner: | Unassigned |
| Serial No.: | Unassigned | Group Art Unit: | Unassigned |
| Filed: | Herewith | Docket: | 16791 (03006) |
| For: | Extraordinary Piezoconductance in Inhomogeneous Semiconductors | Dated: | July 24, 2003 |

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, it is requested that the following references, which are also listed on the attached Form PTO-1449, be made of record in the above-identified case.

1. US Patent No.: 5,663,507, dated September 2, 1997, issued to Robert M. Westervelt, et al.;
2. T. Zhou, et al.; "Extraordinary magnetoresistance in externally shunted van der Pauw plates"; Applied Physics Letters; Vol. 78; No. 5; pp. 667-69; (2001);
3. S.A. Solin, et al.; "Nonmagnetic semiconductors as read-head sensors for ultra-high-density magnetic recording"; Applied Physics Letters; Vol. 80; No. 21; pp. 4012-14; (2002);

CERTIFICATE OF MAILING BY "EXPRESS MAIL"

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I hereby certify that this correspondence is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 C.F.R. § 1.10 on the date indicated above and is addressed to the Commissioner for Patents, Box 1450, Alexandria, VA 22313-1450 on July 24, 2003.

Dated: July 24, 2003



Paul J. Esatto, Jr., Esq.

4. A.C.H. Rowe, et al.; "A uniaxial tensile stress apparatus for temperature-dependent magnetotransport and optical studies of thin films"; Review of Scientific Instruments; Vol. 73; No. 12; pp. 4270-76; (2002)
5. S.A. Solin, et al.; "Enhanced Room-Temperature Geometric Magnetoresistance in Inhomogeneous Narrow-Gap Semiconductors"; Science; Vol. 289; pp. 1530-32; (2000)
6. C.A. Mead, et al.; "Fermi Level Position at Metal-Semiconductor Interfaces"; Physical Review; Vol. 134; No. 3A; pp. A713-16; (1964);
7. G. Margaritondo; "Interface states at semiconductor junctions"; Rep. Prog. Phys.; Vol. 62; pp. 7650-808; (1999)
8. C.S. Gworek, et al.; "Pressure dependence of Cu, Ag, and Fe/n-GaAs Schottky barrier heights"; Phy. Rev.B; Vol. 64; pp. 045322-1 – 6; (2001)
9. Peter Van Vessel et al.; "Rediscovering the Strain Gauge Pressure Sensor"; Sensors; 8 pps.; (1999);
10. Adhesives List printed from www.tokyoosokki.co.jp/e/product...; on 6/27/2003;
11. Fujidura Semiconductor Pressure Sensors printed from www.fujidura.co.jp/sensor/press/intro... on 6/27/2003; and
12. Y. Ohmura; "Piezoresistance Effect in p-Type Semiconductors Si and Ge"; 21st International Conference on The Physics of Semiconductors; Vol. 1; pp. 273-76; (1992).

Applicants are submitting copies of the above-cited references.

Inasmuch as this Information Disclosure Statement is being submitted in accordance with the schedule set out in 37 C.F.R. § 1.97(b), no statement or fee is required.

Respectfully submitted,



Paul J. Esatto, Jr.

Registration No.: 30,749

Scully, Scott, Murphy & Presser
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Garden City, New York 11530
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PJE:RFH:rjl

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| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | Docket Number (Optional) 16791 (03006) | Application Number Unassigned |
| | Applicant(s) Alistair C.H. Rowe, et al. | |
| | Filing Date Herewith | Group Art Unit Unassigned |

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| U.S. PATENT DOCUMENTS |
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| *EXAMINER INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----|-----------------|----------|--------------------|-------|----------|-------------------------------|
| | | 5,663,507 | 09/02/97 | Westervelt, et al. | | | |
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| OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i> |
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| | T. Zhou, et al.; "Extraordinary magnetoresistance in externally shunted van der Pauw plates"; <u>Applied Physics Letters</u> ; Vol. 78; No. 5; pp. 667-69; (2001) |
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| | | C.A. Mead, et al.; "Fermi Level Position at Metal-Semiconductor Interfaces"; <u>Physical Review</u> ; Vol. 134; No. 3A; pp. A713-16; (1964) |
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| | | Adhesives List printed from www.tokynosokki.co.jp/e/product . . . ; on 6/27/2003 |
| | | Fujidura Semiconductor Pressure Sensors printed from www.fujidura.co.jp/sensor/press/intro . . ." on 6/27/2003 |
| | | Y. Ohmura; "Piezoresistance Effect in p-Type Semiconductors Si and Ge"; 21 st International Conference on The Physics of Semiconductors; Vol. 1; pp. 273-76; (1992 |
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